

**N-Ch and P-Ch 30V Fast Switching MOSFETs**
**General Description**

The UM3304 is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The UM3304 meet the RoHS and Green Product requirement with full function reliability approved.

**Features**

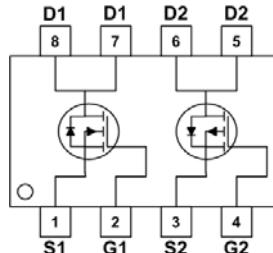
- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

**Product Summary**

BVDSS	RDS(on)	ID
30V	45mΩ	4.6A
-30V	125mΩ	-3A

**Applications**

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- CCFL Back-light Inverter

**SOP8 Pin Configuration**

**Absolute Maximum Ratings**

Symbol	Parameter	Rating		Units
		N-Ch	P-Ch	
V <sub>DS</sub>	Drain-Source Voltage	30	-30	V
V <sub>GS</sub>	Gate-Source Voltage	±20	±20	V
I <sub>D</sub> @T <sub>A</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	4.6	-3	A
I <sub>D</sub> @T <sub>A</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	3.7	-2.3	A
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	9.2	-6	A
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>4</sup>	1.5	1.5	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

**Thermal Data**

Symbol	Parameter	Typ.	Max.	Unit
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>	---	85	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>	---	60	°C/W

**N-Ch and P-Ch 30V Fast Switching MOSFETs**
**N-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	30	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	BVDSS Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$	---	0.016	---	$\text{V}/^\circ\text{C}$
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=10\text{V}$ , $I_D=4\text{A}$	---	38	45	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$ , $I_D=2\text{A}$	---	56	70	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250\mu\text{A}$	1.0	1.5	2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient		---	-3.04	---	$\text{mV}/^\circ\text{C}$
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=24\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=25^\circ\text{C}$	---	---	1	$\mu\text{A}$
		$V_{DS}=24\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=55^\circ\text{C}$	---	---	5	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$ , $V_{DS}=0\text{V}$	---	---	$\pm 100$	nA
$g_{fs}$	Forward Transconductance	$V_{DS}=5\text{V}$ , $I_D=4\text{A}$	---	8	---	S
$R_g$	Gate Resistance	$V_{DS}=0\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	2.3	4.6	$\Omega$
$Q_g$	Total Gate Charge (4.5V)	$V_{DS}=20\text{V}$ , $V_{GS}=4.5\text{V}$ , $I_D=4\text{A}$	---	2.75	---	nC
$Q_{gs}$	Gate-Source Charge		---	0.67	---	
$Q_{gd}$	Gate-Drain Charge		---	1.52	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=15\text{V}$ , $V_{GS}=10\text{V}$ , $R_G=3.3\Omega$	---	3.6	---	ns
$T_r$	Rise Time		---	14.6	---	
$T_{d(off)}$	Turn-Off Delay Time		---	11.5	---	
$T_f$	Fall Time		---	1.9	---	
$C_{iss}$	Input Capacitance	$V_{DS}=15\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	220	---	pF
$C_{oss}$	Output Capacitance		---	38	---	
$C_{rss}$	Reverse Transfer Capacitance		---	32	---	

**Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current <sup>1,4</sup>	$V_G=V_D=0\text{V}$ , Force Current	---	---	4.6	A
$I_{SM}$	Pulsed Source Current <sup>2,4</sup>		---	---	9.2	A
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0\text{V}$ , $I_s=1\text{A}$ , $T_J=25^\circ\text{C}$	---	---	1	V

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
- 3.The power dissipation is limited by  $150^\circ\text{C}$  junction temperature
- 4.The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

**N-Ch and P-Ch 30V Fast Switching MOSFETs**
**P-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)**

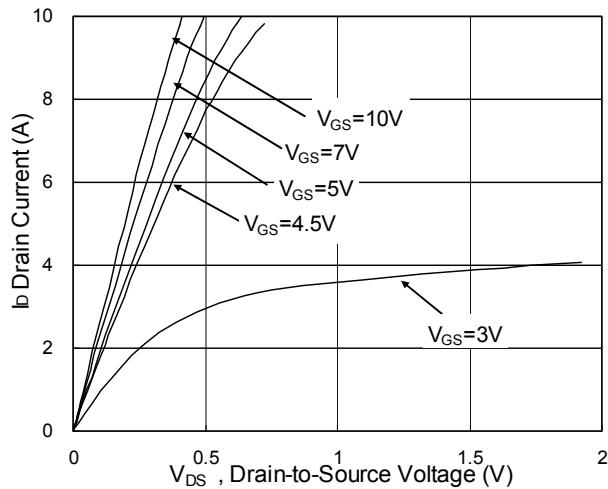
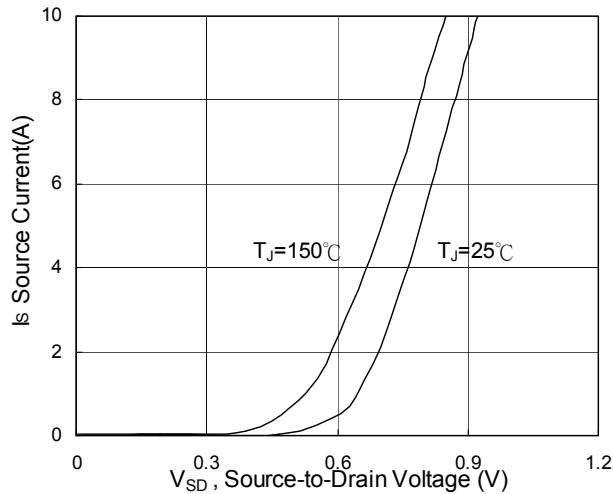
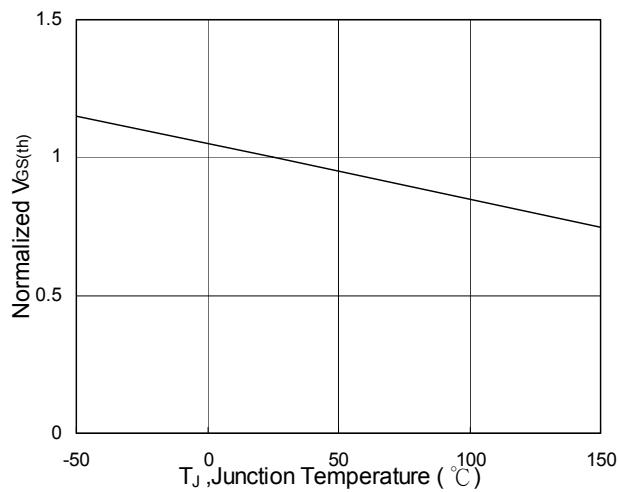
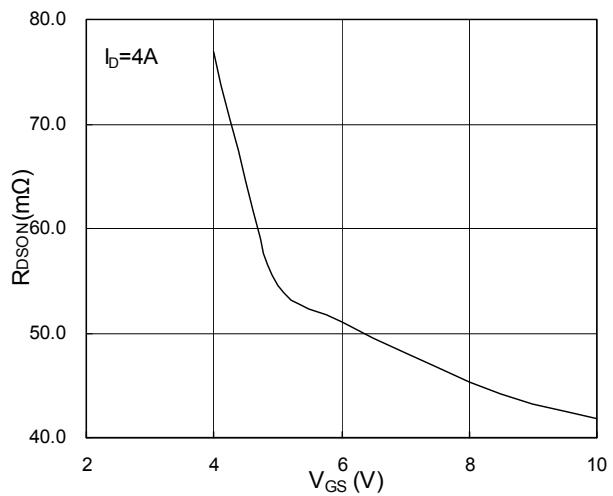
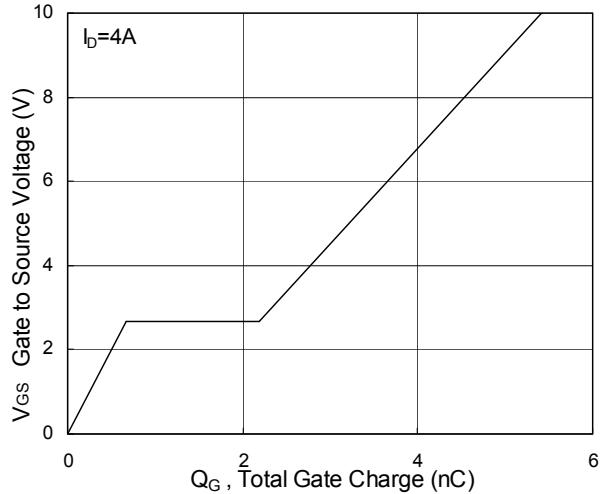
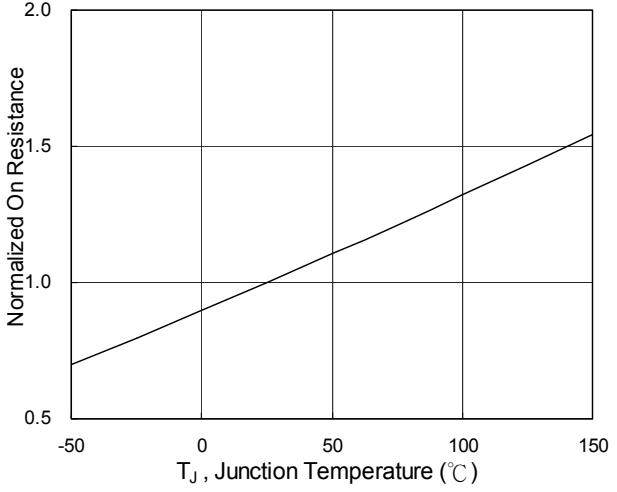
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=-250\mu\text{A}$	-30	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	$BV_{DSS}$ Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=-1\text{mA}$	---	-0.02	---	$\text{V}/^\circ\text{C}$
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=-10\text{V}$ , $I_D=-3\text{A}$	---	105	125	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}$ , $I_D=-1.5\text{A}$	---	180	215	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=-250\mu\text{A}$	-1.0	-1.5	-2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient		---	3.72	---	$\text{mV}/^\circ\text{C}$
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=-24\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=25^\circ\text{C}$	---	---	1	$\mu\text{A}$
		$V_{DS}=-24\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=55^\circ\text{C}$	---	---	5	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$ , $V_{DS}=0\text{V}$	---	---	$\pm 100$	nA
$g_{fs}$	Forward Transconductance	$V_{DS}=-5\text{V}$ , $I_D=-3\text{A}$	---	3.8	---	S
$R_g$	Gate Resistance	$V_{DS}=0\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	26	52	$\Omega$
$Q_g$	Total Gate Charge (-4.5V)	$V_{DS}=-20\text{V}$ , $V_{GS}=-4.5\text{V}$ , $I_D=-1\text{A}$	---	3.3	---	nC
$Q_{gs}$	Gate-Source Charge		---	0.88	---	
$Q_{gd}$	Gate-Drain Charge		---	1.55	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=-15\text{V}$ , $V_{GS}=-10\text{V}$ , $R_G=3.3\Omega$ , $I_D=-1\text{A}$	---	9.6	---	ns
$T_r$	Rise Time		---	6.7	---	
$T_{d(off)}$	Turn-Off Delay Time		---	21.5	---	
$T_f$	Fall Time		---	3.3	---	
$C_{iss}$	Input Capacitance	$V_{DS}=-15\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	203	---	pF
$C_{oss}$	Output Capacitance		---	42	---	
$C_{rss}$	Reverse Transfer Capacitance		---	34	---	

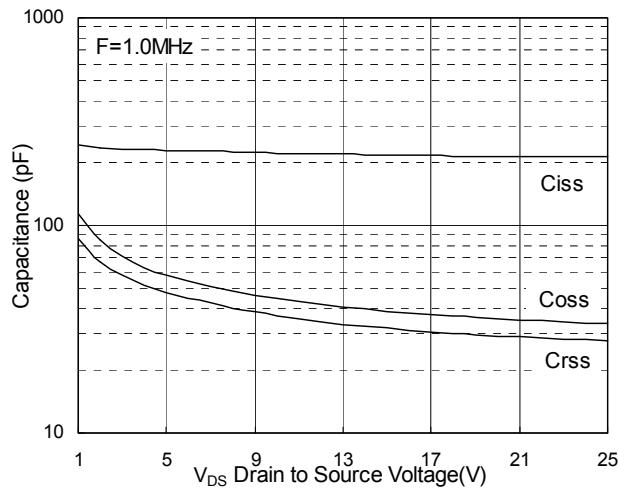
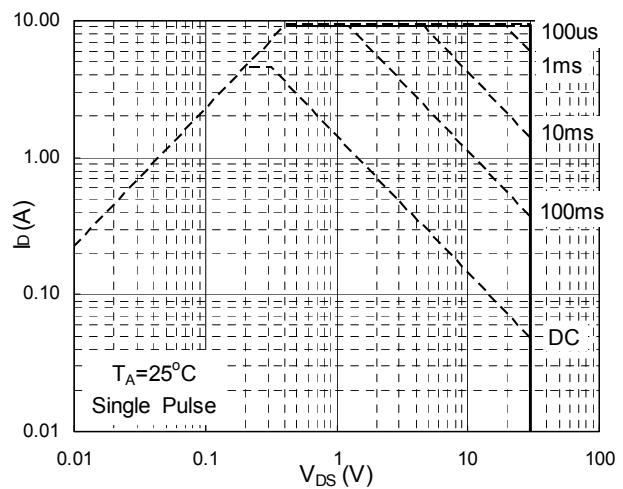
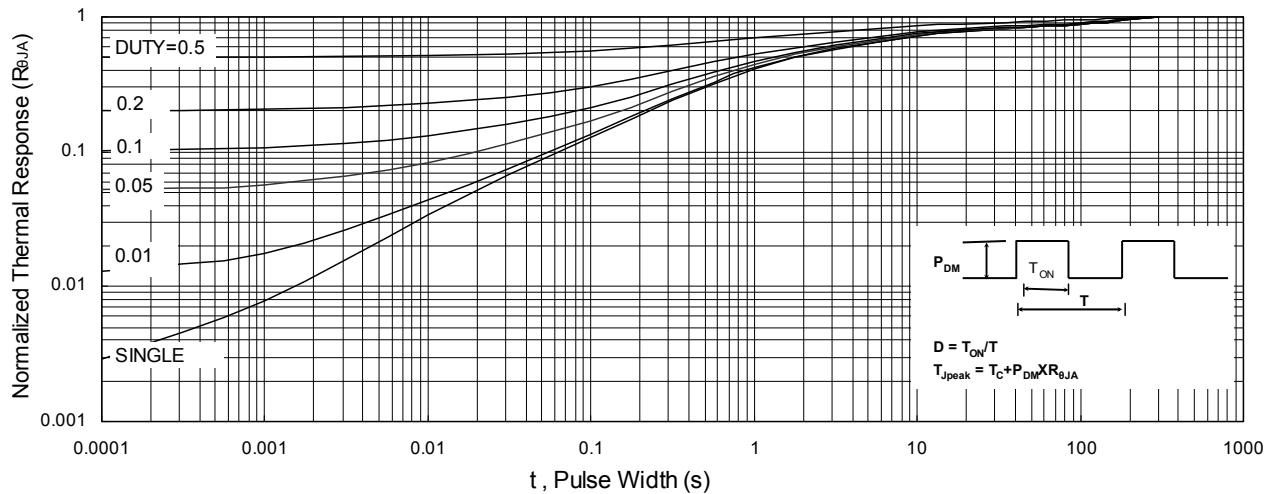
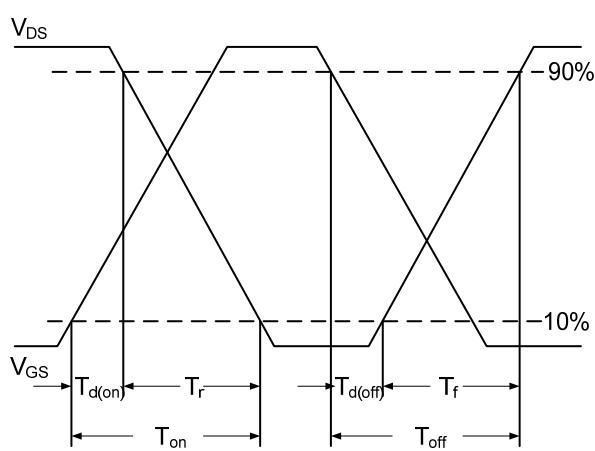
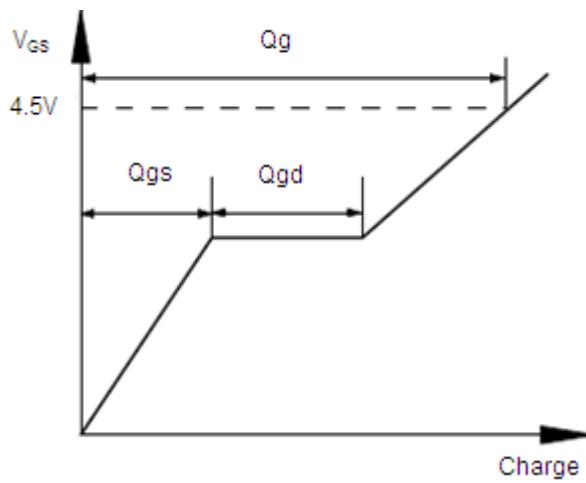
**Diode Characteristics**

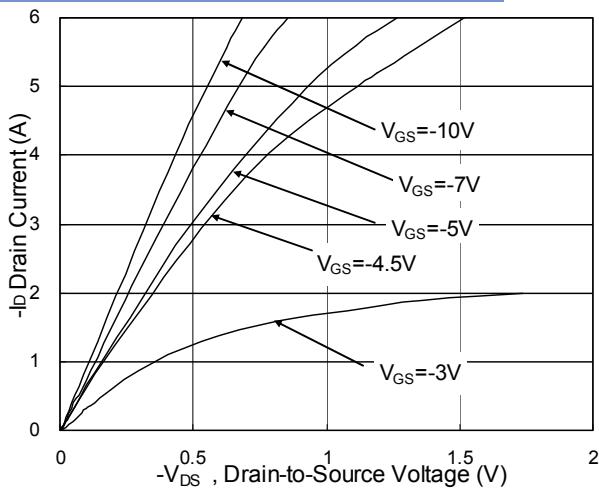
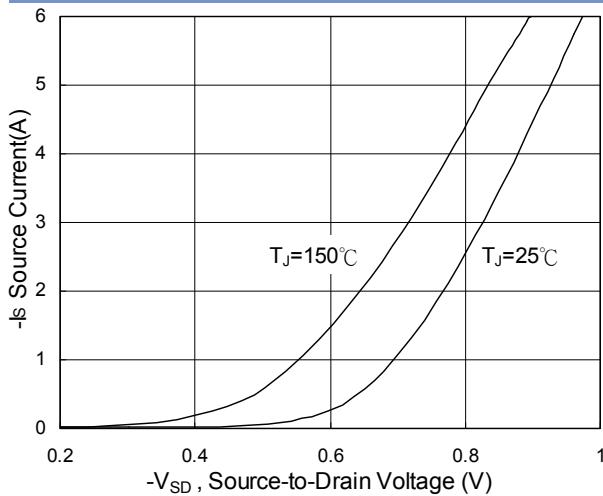
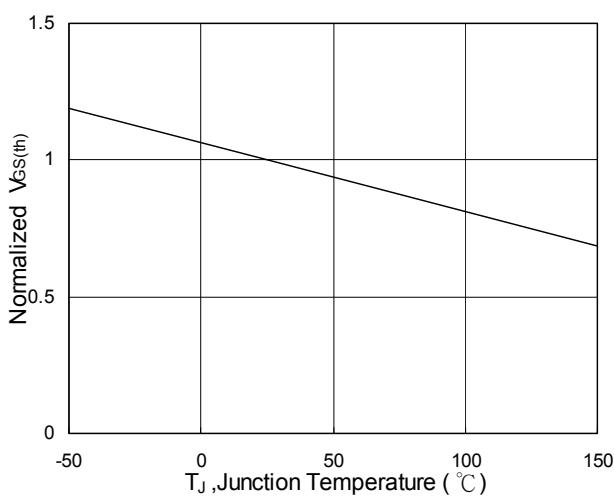
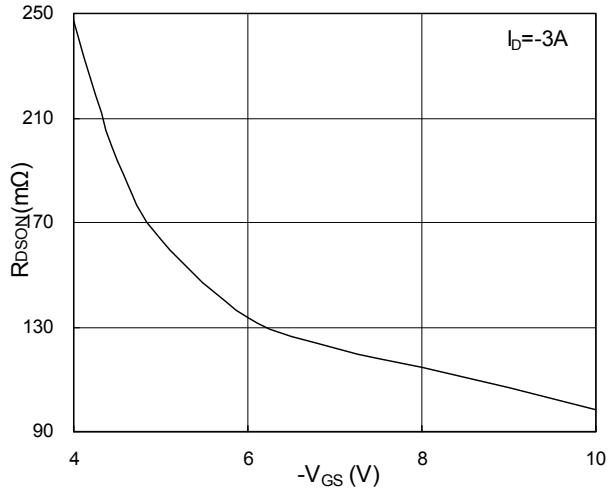
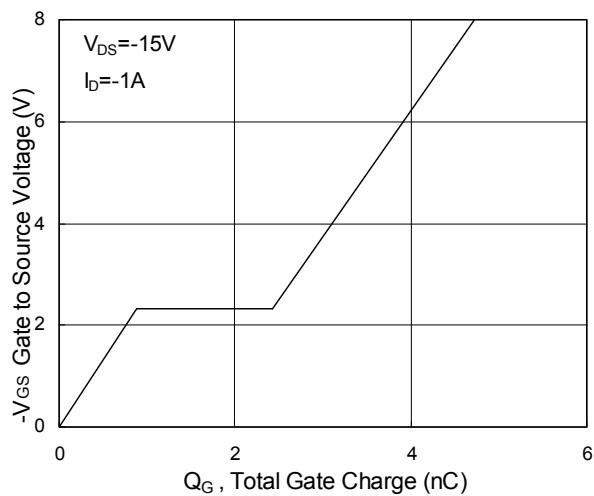
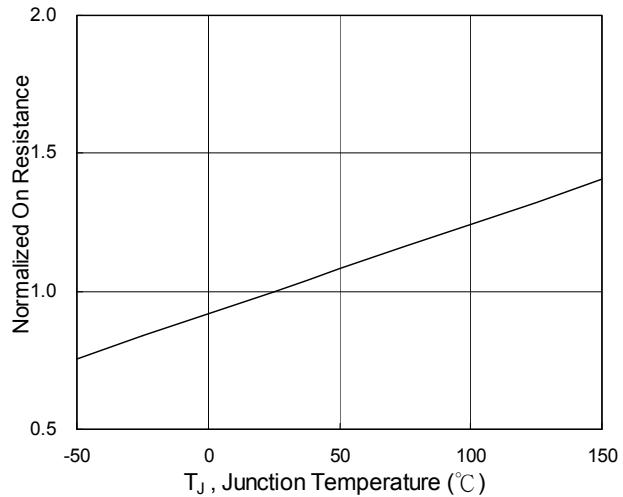
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$I_{SM}$	Pulsed Source Current <sup>2,4</sup>		---	---	-6	A
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0\text{V}$ , $I_s=-1\text{A}$ , $T_J=25^\circ\text{C}$	---	---	-1.2	V

Note :

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**N-Channel Typical Characteristics**

**Fig.1 Typical Output Characteristics**

**Fig.3 Forward Characteristics of Reverse**

**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$** 
**N-Ch and P-Ch 30V Fast Switching MOSFETs**

**Fig.2 On-Resistance vs. G-S Voltage**

**Fig.4 Gate-charge Characteristics**

**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**

**N-Ch and P-Ch 30V Fast Switching MOSFETs**

**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

**Fig.9 Normalized Maximum Transient Thermal Impedance**

**Fig.10 Switching Time Waveform**

**Fig.11 Gate Charge Waveform**

**N-Ch and P-Ch 30V Fast Switching MOSFETs**
**N-Channel Typical Characteristics**

**Fig.1 Typical Output Characteristics**

**Fig.3 Forward Characteristics of Reverse**

**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$** 

**Fig.2 On-Resistance v.s Gate-Source**

**Fig.4 Gate-Charge Characteristics**

**Fig.6 Normalized  $R_{DS(on)}$  v.s  $T_J$**

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